

Notice of References Cited	Application/Control No. 10/734,008	Applicant(s)/Patent Under Reexamination BUNCH ET AL.	
	Examiner John L. Goff	Art Unit 1733	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0069331	04-2003	Teiichi et al.	523/176
*	B	US-4,376,194	03-1983	Tanaka et al.	528/288
	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	WO 01/60938 08-2001 Teiichi et al.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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